Applicant(s)/Patent Under Reexamination 10/511,727 NISHIO, AKIHIKO Notice of References Cited Art Unit Examiner

Application/Control No.

Page 1 of 2 2618 **Bobbak Safaipour**

U.S. PATENT DOCUMENTS

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0055367 A1	05-2002	Hamabe et al.	455/522
*	В	US-2002/0115467 A1	08-2002	Hamabe, Kojiro	455/522
*	С	US-2002/0160783 A1	10-2002	Holtzman et al.	455/452
*	٥	US-2002/0160798 A1	10-2002	Shoji et al.	455/522
*	E	US-2004/0029534 A1	02-2004	Odenwalder, Joseph P.	455/67.11
*	F	US-2004/0110524 A1	06-2004	Takano et al.	455/522
*	G	US-6,760,587 B2	07-2004	Holtzman et al.	455/436
*	Н	US-2005/0043051 A1	02-2005	Takano et al.	455/522
*	1	US-2005/0075124 A1	04-2005	Willenegger et al.	455/522
*	J	US-2005/0186981 A1	08-2005	Nishio, Akihiko	455/522
*	К	US-6,961,582 B2	11-2005	Su et al.	455/522
*	L	US-6,999,784 B1	02-2006	Choi, Seung Woog	455/522
*	М	US-7,027,828 B2	04-2006	Kim et al.	455/522

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Ρ		,			·
	α					
	R					
	ø					
	T					

NON-PATENT DOCUMENTS

	MONTALLIN BOODMENTO						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	υ						
	>						
	w						
	x						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classif ications may be US or foreign.

ć . . .

Notice of References Cited Application/Control No. 10/511,727 Applicant(s)/Patent Under Reexamination NISHIO, AKIHIKO Examiner Bobbak Safaipour Art Unit Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,263,205 B1	07-2001	Yamaura et al.	455/442
*	В	US-6,714,788 B2	03-2004	Voyer, Nicolas	455/453
*	С	US-2005/0277419 A1	12-2005	Takano et al.	455/442
*	D	US-2006/0045046 A1	03-2006	Kim et al.	370/329
*	Ε	US-2002/0061764 A1	05-2002	Kim et al.	455/522
*	F	US-2003/0231612 A1	12-2003	Kim et al.	370/342
*	G	US-7,058,035 B2	06-2006	English, Sean	370/332
	H	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	υ		
	>		
	w		
	x	(C. MDED C 707 05(a))	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classif ications may be US or foreign.